Acta Crystallographica Section E

## Structure Reports

Online
ISSN 1600-5368

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## Key indicators

Single-crystal X-ray study
$T=178 \mathrm{~K}$
Mean $\sigma(\mathrm{C}-\mathrm{C})=0.004 \AA$
$R$ factor $=0.028$
$w R$ factor $=0.071$
Data-to-parameter ratio $=14.7$

For details of how these key indicators were
automatically derived from the article, see http://journals.iucr.org/e.
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# $\operatorname{Bis}\left(\eta^{5}\right.$-pentamethylcyclopentadienyl) [bis- $\eta^{5}$ -syn-[2.2](4,7)indenophanyl]diruthenium(II) 

In the title compound, $\left[\mathrm{Ru}_{2}\left(\mathrm{C}_{10} \mathrm{H}_{15}\right)_{2}\left(\mathrm{C}_{22} \mathrm{H}_{18}\right)\right]$, the four fivemembered rings are approximately eclipsed. The distances from these rings to the corresponding Ru atoms are 1.795 (1) and 1.798 (1) $\AA$ for the Cp*, and 1.835 (1) and 1.842 (1) $\AA$ for the indenyl five-membered rings.

## Comment

Having prepared and studied various metal complexes of anti[2.2]indenophanes (Hopf \& Dannheim, 1988), we have now prepared ruthenium complexes of syn-[2.2]indenophane, (1). Whereas with the former ligands the metal atoms are oriented in a stepwise fashion, in (1) they were expected to be oriented above each other (eclipsed). Here we present the structure of the doubly capped ruthenium complex, (3).


Received 16 January 2003 Accepted 20 January 2003 Online 31 January 2003


Figure 1
The molecule of compound (3) in the crystal. Displacement ellipsoids are shown at the $30 \%$ probability level. H atoms have been omitted for clarity.


Figure 2
Alternative view of compound (3), perpendicular to the plane of ring C19-C23. Radii are arbitrary.
tively, out of the plane of the four other atoms; the interplanar angle between the four-atom planes is $1.90(2)^{\circ}$, and the distance between the corresponding centroids is $3.08 \AA$.

## Experimental

Hydrocarbon (1) was monometalated using methyl lithium in THF at 233 K . The mixture was stirred for 30 min at 273 K and the pentamethylcyclopentadienyl ruthenium chloride tetramer was then added. Reaction was complete after 1 h at room temperature. The solvent was removed in vacuo and the remaining solid recrystallized from hexane; the monoruthenium complex, (2), was isolated in $92 \%$ yield as yellow needles and characterized by spectroscopic and analytical data. Repetition of the reaction sequence furnished the bisruthenium complex, (3), as yellow prisms in $91 \%$ yield. Spectroscopic
data are again in full accord with the structural assignment. For full details, see Hartig (1991).

## Crystal data

$$
\begin{aligned}
& {\left[\mathrm{Ru}_{2}\left(\mathrm{C}_{10} \mathrm{H}_{15}\right)_{2}\left(\mathrm{C}_{22} \mathrm{H}_{18}\right)\right]} \\
& M_{r}=754.94 \\
& \text { Monoclinic, } P 2_{1} / c \\
& a=8.647(2) \AA \\
& b=13.604(4) \AA \\
& c=28.959(8) \AA \\
& \beta=92.41(2)^{\circ} \\
& V=3403.5(16) \AA^{3} \\
& Z=4 \\
& \text { Data collection }
\end{aligned}
$$

| Nicolet $R 3$ diffractometer | $R_{\text {int }}=0.020$ |
| :--- | :--- |
| $\omega-2 \theta$ scans | $\theta_{\max }=25.0^{\circ}$ |
| Absorption correction: refined from | $h=0 \rightarrow 10$ |
| $\quad \Delta F(D I F A B S$; Walker \& Stuart, | $k=-16 \rightarrow 10$ |
| $1983)$ | $l=-34 \rightarrow 34$ |

$T_{\text {min }}=0.66, T_{\text {max }}=0.84$
11146 measured reflections
5984 independent reflections
5079 reflections with $I>2 \sigma(I)$

## Refinement

Refinement on $F^{2}$
$R\left[F^{2}>2 \sigma\left(F^{2}\right)\right]=0.028$
$w R\left(F^{2}\right)=0.071$
$S=1.05$
5984 reflections
407 parameters
H -atom parameters constrained
$D_{x}=1.473 \mathrm{Mg} \mathrm{m}^{-3}$
Mo $K \alpha$ radiation
Cell parameters from 50 reflections
$\theta=10-11.5^{\circ}$
$\mu=0.92 \mathrm{~mm}^{-1}$
$T=178$ (2) K
Prism, yellow
$0.70 \times 0.40 \times 0.15 \mathrm{~mm}$
$R_{\text {int }}=0.020$
$\theta_{\text {max }}=25.0^{\circ}$
$h=0 \rightarrow 10$
$l=-34 \rightarrow 34$
3 standard reflections every 147 reflections intensity decay: none

$$
\begin{gathered}
w=1 /\left[\sigma^{2}\left(F_{o}{ }^{2}\right)+(0.0398 P)^{2}\right. \\
+1.6478 P] \\
\text { where } P=\left(F_{o}{ }^{2}+2 F_{c}^{2}\right) / 3 \\
(\Delta / \sigma)_{\max }=0.002 \AA^{-3} \\
\Delta \rho_{\max }=0.42 \mathrm{e} \AA^{-3} \\
\Delta \rho_{\min }=-0.61 \mathrm{e}^{-3}
\end{gathered}
$$

Methyl H atoms were identified in difference syntheses, idealized and then refined using rigid methyl groups allowed to rotate but not tip. Other H atoms were included using a riding model, with fixed $\mathrm{C}-$ H bond lengths (aromatic $\mathrm{C}-\mathrm{H}=0.95 \AA$, and methyl and methylene $\mathrm{C}-\mathrm{H}=0.99 \AA) ; U_{\text {iso }}(\mathrm{H})$ values were fixed at $1.2 U_{\text {eq }}$ of the parent atom.

Data collection: P3 (Nicolet, 1987); cell refinement: P3; data reduction: XDISK (Nicolet, 1987); program(s) used to solve structure: SHELXS97 (Sheldrick, 1990); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: XP (Siemens, 1994); software used to prepare material for publication: SHELXL97.

Financial support from the Fonds der Chemischen Industrie is gratefully acknowledged. We thank Mr A. Weinkauf for technical assistance.

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